

CR05AS Series

Sensitive Gate Silicon Controlled Rectifiers

Reverse Blocking Thyristors

PNPN devices designed for high volume, line-powered consumer applications such as relay and lamp drivers, small motor controls, gate drivers for larger thyristors, and sensing and detection circuits. Supplied in an inexpensive plastic SOT-89 package which is readily adaptable for use in automatic insertion equipment.

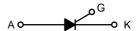
- Sensitive Gate Allows Triggering by Microcontrollers and Other Logic Circuits
- Blocking Voltage to 800 V
- On-State Current Rating of 0.8 Amperes RMS at 80°C
- High Surge Current Capability 10 A
- Minimum and Maximum Values of IGT, VGT and IH Specified for Ease of Design
- Immunity to dV/dt 20 V/μsec Minimum at 110°C
- Glass-Passivated Surface for Reliability and Uniformity

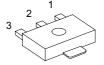
MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage ^(Note 1) (T _J = -40 to 110°C, Sine Wave, 50 to 60 Hz; Gate Open) CR05AS-3 CR05AS-4 CR05AS-6 CR05AS-8	V _{DRM} , V _{RRM}	300 400 600 800	V
On-State RMS Current (T _C = 80°C) 180° Conduction Angles	I _{T(RMS)}	0.8	А
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave, 60 Hz, T _J = 25°C)	I _{TSM}	10	A
Circuit Fusing Consideration (t = 8.3 ms)	I ² t	0.415	A ² s
Forward Peak Gate Power (T _A = 25°C, Pulse Width ≤ 1.0 μs)	P _{GM}	0.1	W
Forward Average Gate Power (T _A = 25°C, t = 8.3 ms)	P _{G(AV)}	0.10	W
Forward Peak Gate Current (T _A = 25°C, Pulse Width ≤ 1.0 μs)	I _{GM}	1.0	Α
Reverse Peak Gate Voltage (T _A = 25°C, Pulse Width ≤ 1.0 μs)	V_{GRM}	5.0	V
Operating Junction Temperature Range @ Rate V _{RRM} and V _{DRM}	TJ	–40 to 110	°C
Storage Temperature Range	T _{stg}	–40 to 150	°C

⁽¹⁾ VDRM and VRRM for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant source such that the voltage ratings of the devices are exceeded.

SCR 0.8 AMPERES RMS 300 thru 800 VOLTS





SOT-89

PIN ASSIGNMENT		
1	Gate	
2	Anode	
3	Cathode	

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THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance – Junction–to–Case – Junction–to–Ambient	$R_{ hetaJC} \ R_{ hetaJA}$	75 200	°C/W
Lead Solder Temperature (<1/16" from case, 10 secs max)	T _L	260	°C

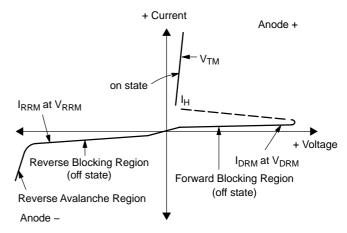
ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS	-		_	•		•
Peak Repetitive Forward or Reverse Blocking Current (V_D = Rated V_{DRM} and V_{RRM} ; R_{GK} = 1 $k\Omega$)	$T_{C} = 25^{\circ}C$ $T_{C} = 110^{\circ}C$	I _{DRM} , I _{RRM}		_ _	10 100	μΑ
ON CHARACTERISTICS	•					
Peak Forward On–State Voltage* (I _{TM} = 1.0 A Peak @ T _A = 25°C)		V_{TM}	-	_	1.7	V
Gate Trigger Current (Continuous dc) ^(Note 3) ($V_{AK} = 7.0 \text{ Vdc}, R_L = 100 \Omega$)	T _C = 25°C	I _{GT}	_	40	200	μΑ
Holding Current ⁽²⁾ (V _{AK} = 7.0 Vdc, Initiating Current = 20 mA)	$T_C = 25^{\circ}C$ $T_C = -40^{\circ}C$	l _Η		0.5 —	5.0 10	mA
Latch Current $(V_{AK} = 7.0 \text{ V}, \text{ Ig} = 200 \mu\text{A})$	$T_C = 25^{\circ}C$ $T_C = -40^{\circ}C$	ΙL		0.6 —	10 15	mA
Gate Trigger Voltage (Continuous dc) ^(Note 3) $(V_{AK} = 7.0 \text{ Vdc}, R_L = 100 \Omega)$ $T_C = -40^{\circ}\text{C}$	T _C = 25°C	V _{GT}	_	0.62 —	0.8 1.2	V
DYNAMIC CHARACTERISTICS						
Critical Rate of Rise of Off–State Voltage $(V_D = Rated V_{DRM}, Exponential Waveform, R_{GK} = 1)$	000 Ω,T _J = 110°C)	dV/dt	20	35	_	V/µs
Critical Rate of Rise of On–State Current (I _{PK} = 20 A; Pw = 10 μsec; diG/dt = 1 A/μsec, Igt = 2	20 mA)	di/dt		_	50	A/μs

^{*}Indicates Pulse Test: Pulse Width \leq 1.0 ms, Duty Cycle \leq 1%. 2. R_{GK} = 1000 Ω included in measurement. 3. Does not include R_{GK} in measurement.

Voltage Current Characteristic of SCR

Symbol	Parameter
V _{DRM}	Peak Repetitive Off State Forward Voltage
I _{DRM}	Peak Forward Blocking Current
V_{RRM}	Peak Repetitive Off State Reverse Voltage
I _{RRM}	Peak Reverse Blocking Current
V_{TM}	Peak on State Voltage
I _H	Holding Current



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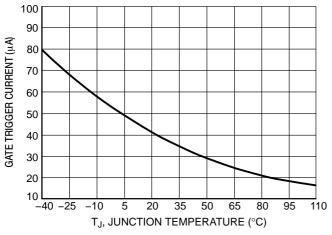


Figure 1. Typical Gate Trigger Current versus Junction Temperature

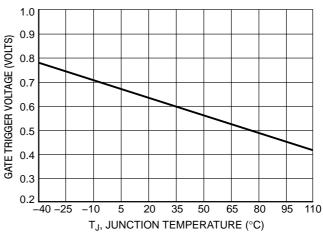


Figure 2. Typical Gate Trigger Voltage versus
Junction Temperature

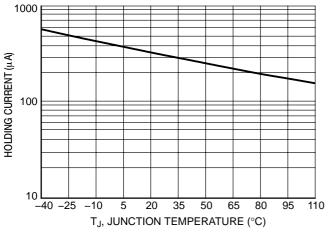


Figure 3. Typical Holding Current versus Junction Temperature

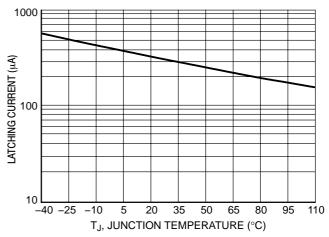


Figure 4. Typical Latching Current versus Junction Temperature

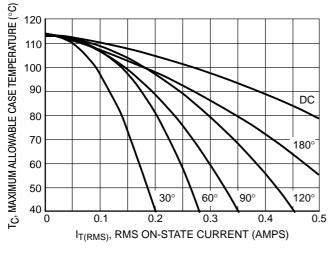


Figure 5. Typical RMS Current Derating

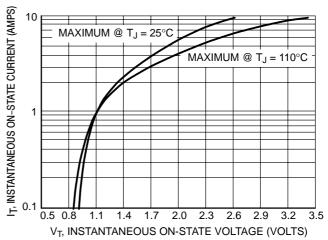


Figure 6. Typical On-State Characteristics